



Beam Diagnostics for Medical Application

Guest Editor:

Prof. Dr. Paola Scampori

1. Dipartimento di Fisica "Ettore Pancini", Università degli Studi di Napoli Federico II, 80126 Naples, Italy

2. Laboratory for High Energy Physics (LHEP), University of Bern, CH-3012 Bern, Switzerland

Deadline for manuscript submissions:

closed (20 June 2021)

Message from the Guest Editor

Beam diagnostics is a key subject in the field of medical accelerators that, in dealing with patient health, requires very stringent conditions in terms of beam delivery, dose assessment, and isotope production, to name but a few issues.

Today, we have thousands of accelerators all over the world, both for therapy or diagnosis purposes and they cover different types of machines: linear accelerators, cyclotrons, synchrotrons, or synchrocyclotrons.

A deep knowledge of the beam parameters is then essential to advance on the facility performance and also to enlarge the possible applications to improve patient health.

In this Special Issue, we encourage the submission of cutting-edge original research works in the field of beam diagnostics for medical applications, and, in particular, on the most recent instrumentation and technology to improve beam diagnostics. We expect to receive contributions from different medical application areas, such as therapy or diagnosis. Comprehensive review papers are also welcome.





an Open Access Journal by MDPI

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo

Dipartimento di Fisica,
Politecnico di Milano, Piazza L.
da Vinci 32, 20133 Milano, Italy

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science), Inspec, CAPlus / SciFinder, and other databases.

Journal Rank: JCR - Q2 (*Engineering, Multidisciplinary*) / CiteScore - Q1 (*General Engineering*)

Contact Us

Applied Sciences Editorial Office
MDPI, St. Alban-Anlage 66
4052 Basel, Switzerland

Tel: +41 61 683 77 34
www.mdpi.com

mdpi.com/journal/applsci
applsci@mdpi.com
[X@Applsci](https://twitter.com/Applsci)